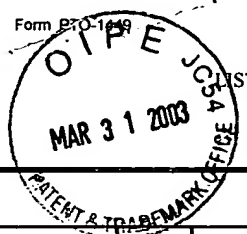

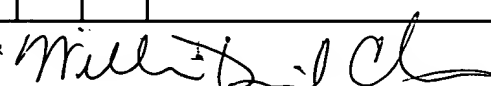


Form PTO-149		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5016(4015)		SERIAL NO. 09/488,973	
 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Christopher L. Parfeniuk et al.			
				FILING DATE January 20, 2000		GROUP 2823	
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	US 2002/0174917 A1	Pub. 11/28/02	Segal et al.			
	AB						
	AC						
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	AE						
	AF						
	AG						
	AH						
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	AL						
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation Yes No
	AM						
	AN						
	AO						
	AP						
	AQ						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
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	AT						
EXAMINER 				DATE CONSIDERED 6/20/03			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Christopher L. Parfeniuk et al.		FILING DATE January 20, 2000	
U.S. PATENT DOCUMENTS				GROUP 2823			

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	4,842,706	06/89	Fukasawa et al.			
AB	4,405,427	09/83	Byrd			
AC	6,391,465 B1	05/02	Zheng et al.			
AD	5,599,467	02/97	Okabe et al.			
AE	5,009,765	04/91	Qamar et al.			
AF	6,085,966	07/00	Shimomuki et al.			
AG	6,227,432 B1	05/01	Enomoto et al.			
AH						
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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
AM	6-65733	03/94	JP			X	
AN							
AO							
AP							
AQ							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)		
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EXAMINER <i>Miller D. Paul</i>	DATE CONSIDERED <i>6/20/03</i>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 <div style="border: 2px solid black; border-radius: 50%; padding: 10px; display: inline-block; transform: rotate(-45deg); transform-origin: center;"> TYPE JAN 30 2003 PATENT & TRADEMARK OFFICE </div>		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 30-5016(4015)		SERIAL NO. 09/488,973	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Christopher L. Parfeniuk et al.		FILING DATE January 20, 2000	
GROUP 2823							

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	US 2002/0003010 A1	Pub 01/10/02	Shah et al.			
	AB						
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	AD						
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FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
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EXAMINER	DATE CONSIDERED 6/20/03
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Form PTO-1449

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30-5016(4015)SERIAL NO.
09/488,973

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Christopher L. Parfeniuk et al.FILING DATE
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*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
AA	6,274,015 B1	08/01	Beier et al.				
AB	5,342,496	08/94	Stellrecht				
AC	6,073,830	06/00	Hunt et al.				
AD	6,199,259 B1	03/01	Demaray et al.				
AE							
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AG							
AH							
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AK							
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
AM	0 881 311 A1	12/98	EPO					
AN	US 01/07404	03/01	PCT Search Report					
AQ								
AP								
AQ								

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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Miller-D. OAC

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